



2 Amps, 500 Volts N-CHANNEL POWER MOSFET

DESCRIPTION

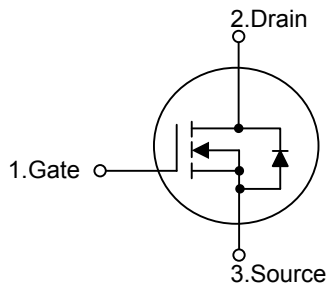
The UTC **2N50** is an N-channel mode power MOSFET using UTC's advanced technology to provide customers with planar stripe and DMOS technology. This technology allows a minimum on-state resistance and superior switching performance. It also can withstand high energy pulse in the avalanche and commutation mode.

The UTC **2N50** is generally applied in high efficiency switch mode power supplies, active power factor correction and electronic lamp ballasts based on half bridge topology.

FEATURES

- * 2A, 500V, $R_{DS(ON)} = 5\Omega$ @ $V_{GS} = 10V$
- * High Switching Speed
- * 100% Avalanche Tested

SYMBOL

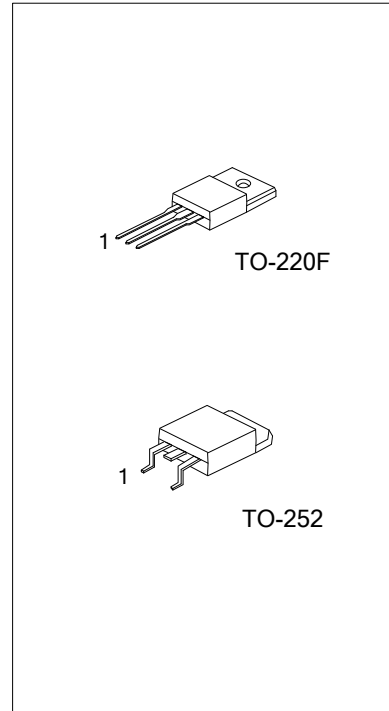


ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
2N50L-TF3-T	2N50G-TF3-T	TO-220F	G	D	S	Tube
2N50L-TN3-R	2N50G-TN3-R	TO-252	G	D	S	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source

2N50L-TF3-T (1) Packing Type (2) Package Type (3) Lead Free		(1) T: Tube, R: Tape Reel (2) TF3: TO-220F, TN3: TO-252 (3) G: Halogen Free, L: Lead Free
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■ **ABSOLUTE MAXIMUM RATINGS** ($T_C=25^\circ\text{C}$, unless otherwise specified)

PARAMETER			SYMBOL	RATINGS	UNIT
Drain-Source Voltage			V _{DSS}	500	V
Gate-Source Voltage			V _{GSS}	±30	V
Drain Current	Continuous (T _C =25°C)		I _D	2 *	A
	Pulsed (Note 1)		I _{DM}	8 *	A
Avalanche Current (Note 1)			I _{AR}	2	A
Avalanche Energy	Single Pulsed		E _{AS}	82	mJ
	Repetitive (Note 3)		E _{AR}	3.3	mJ
Power Dissipation	T _C =25°C	TO-220F	P _D	23	W
		TO-252		50	
	Derate above 25°C	TO-220F		0.18	W/°C
		TO-252		0.4	
Junction Temperature			T _J	+150	°C
Storage Temperature			T _{STG}	-55~+150	°C

Note: Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

* Drain current limited by maximum junction temperature

■ **THERMAL DATA**

PARAMETER		SYMBOL	RATINGS	UNIT
Junction to Ambient	TO-220F	θ_{JA}	62.5	$^\circ\text{C/W}$
	TO-252		110	
Junction to Case	TO-220F	θ_{JC}	5.5	$^\circ\text{C/W}$
	TO-252		2.5	

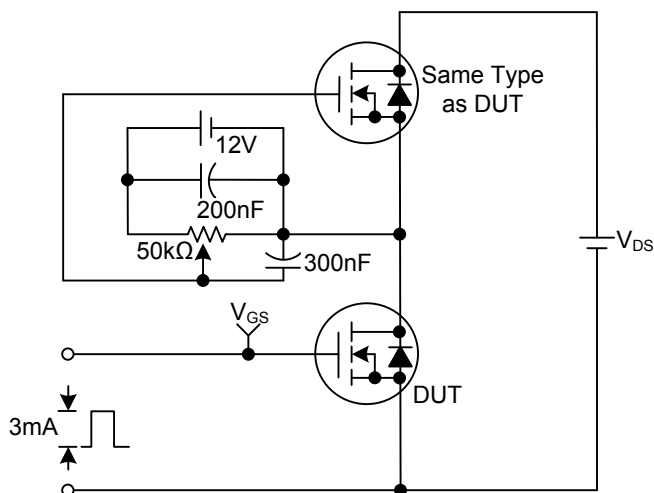
■ **ELECTRICAL CHARACTERISTICS** ($T_C=25^\circ\text{C}$, unless otherwise noted)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	$I_D=250\mu A, V_{GS}=0V$	500			V
Drain-Source Leakage Current		I_{DSS}	$V_{DS}=500V, V_{GS}=0V$			25	μA
Gate- Source Leakage Current	Forward	I_{GSS}	$V_{GS}=+30V, V_{DS}=0V$			+100	nA
	Reverse		$V_{GS}=-30V, V_{DS}=0V$			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	2.0		4.0	V
Static Drain-Source On-State Resistance		$R_{DS(ON)}$	$V_{GS}=10V, I_D=1A$		3.1	5	Ω
DYNAMIC PARAMETERS							
Input Capacitance		C_{ISS}	$V_{GS}=0V, V_{DS}=25V, f=1.0MHz$		236		pF
Output Capacitance		C_{OSS}			40		pF
Reverse Transfer Capacitance		C_{RSS}			22		pF
SWITCHING PARAMETERS							
Total Gate Charge		Q_G	$V_{GS}=10V, V_{DS}=400V, I_D=2A$ (Note 3, 4)		20	25	nC
Gate to Source Charge		Q_{GS}			2	3	nC
Gate to Drain Charge		Q_{GD}			12	15	nC
Turn-ON Delay Time		$t_{D(ON)}$	$V_{DD}=250V, I_D=2A, R_G=25\Omega$ (Note 3, 4)		10		ns
Rise Time		t_R			20		ns
Turn-OFF Delay Time		$t_{D(OFF)}$			60		ns
Fall-Time		t_F			20		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS							
Maximum Body-Diode Continuous Current		I_S				2	A
Maximum Body-Diode Pulsed Current		I_{SM}				8	A
Drain-Source Diode Forward Voltage		V_{SD}	$I_S=2A, V_{GS}=0V$			1.2	V
Body Diode Reverse Recovery Time		t_{RR}	$I_S=2A, V_{GS}=0V, dI_F/dt=100A/\mu s$		300		ns
Body Diode Reverse Recovery Charge		Q_{RR}	(Note 3)		2.1		μC

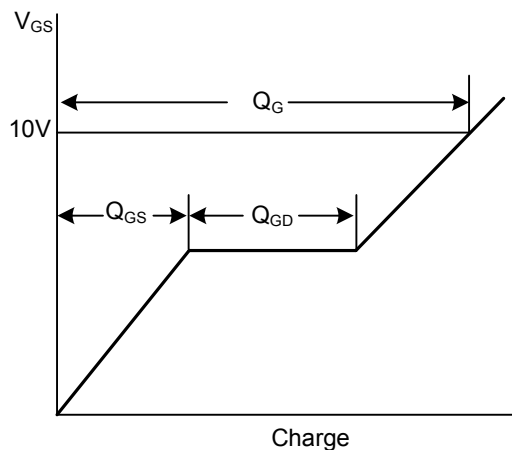
- Notes: 1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. $I_{SD} \leq 2\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$
3. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$
4. Essentially independent of operating temperature

■ TEST CIRCUITS AND WAVEFORMS

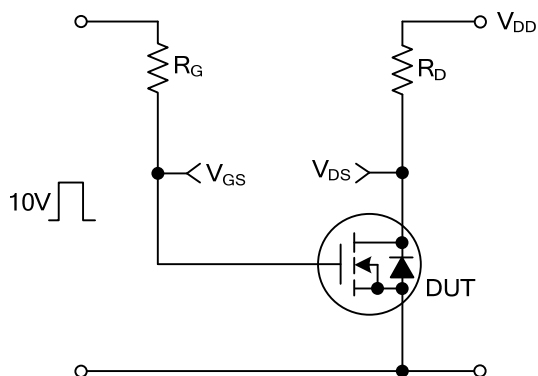
Gate Charge Test Circuit



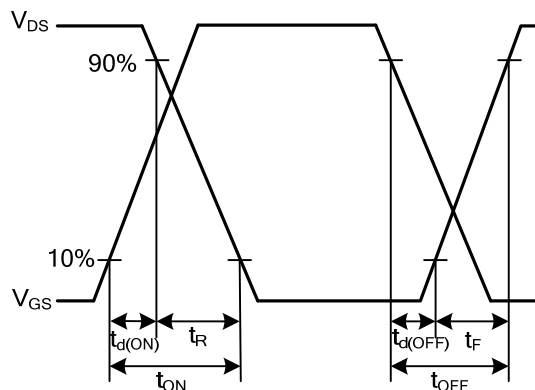
Gate Charge Waveforms



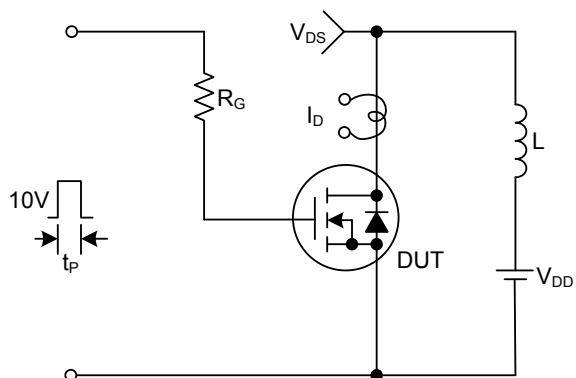
Resistive Switching Test Circuit



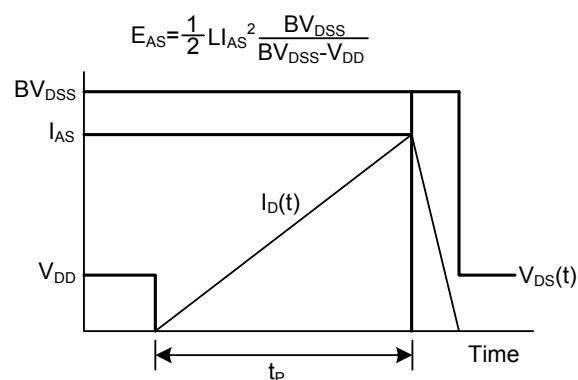
Resistive Switching Waveforms



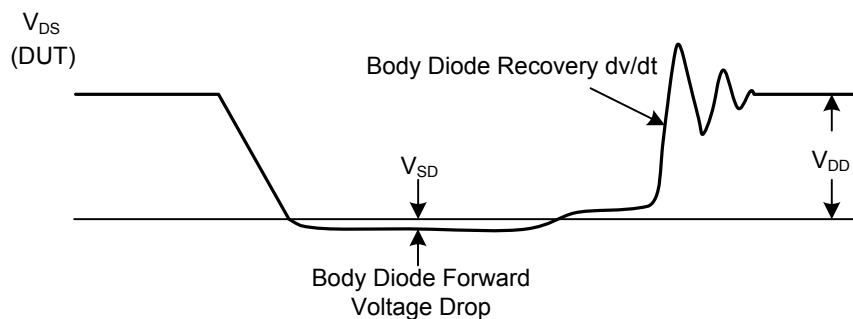
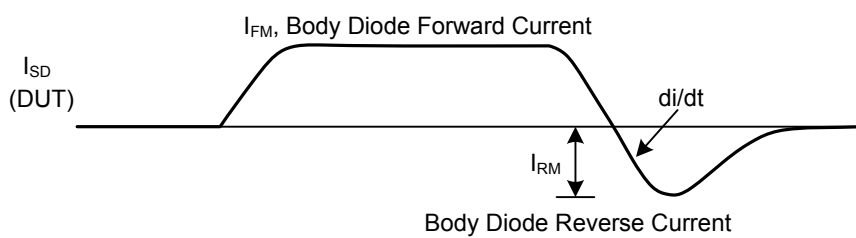
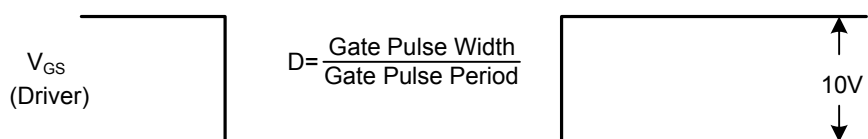
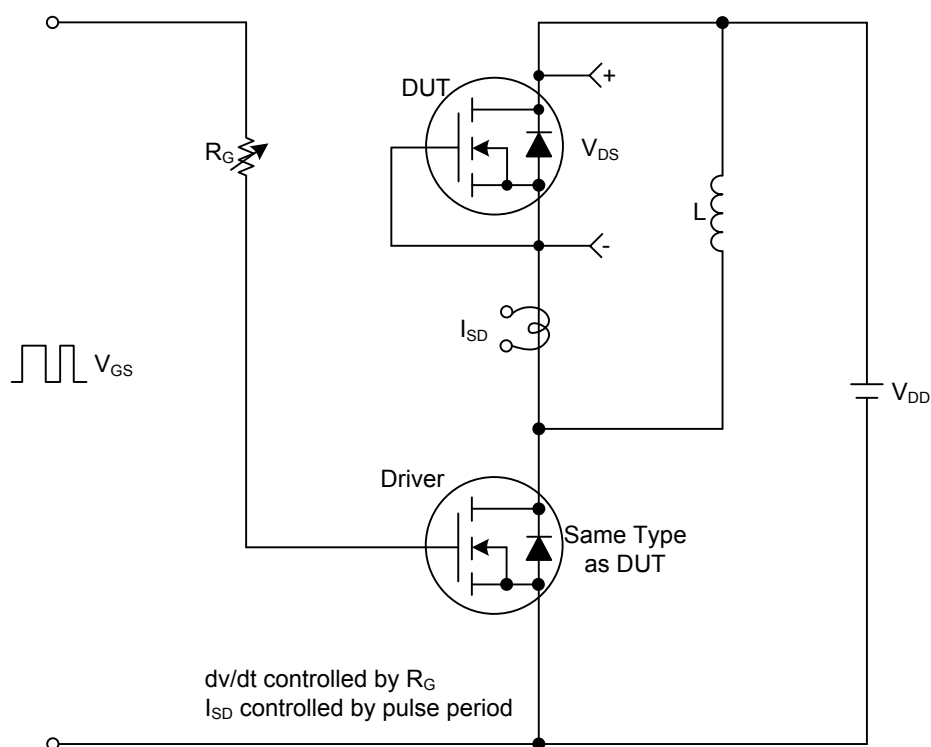
Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms



Peak Diode Recovery dv/dt Test Circuit & Waveforms



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